

EUROPEAN MICROWAVE WEEK 2015

SIX DAYS • THREE CONFERENCES • ONE EXHIBITION

PALAIS DES CONGRÈS, PARIS, FRANCE SEPTEMBER 6 - 11, 2015

Exhibition Opening Hours:

- Tuesday 8th September: 9.30 18.00
- Wednesday 9th September: 9:30 17.30
- Thursday 10th September: 9:30 16.30

SiGe for mm-Wave and THz

Thomas Zimmer

University of Bordeaux, France
thomas.zimmer@ims-bordeaux.fr

WS12: EuMIC - SiGe for mm-Wave and THz



Research in Europe on Bipolar Circuits and Technology

• RF2THz

- Catrene
- Cluster for Application and Technology Research in Europe on NanoElectronics
- www.catrene.org/

DOTSEVEN

- 7th Framework Programme (European commission)
- Integrated Project, section ICT: Information and Communication Technologies
- http://cordis.europa.eu/fp7/ict/programme/



DOTSEVEN at a glance

- Development of a SiGe HBT technology with cut-off frequency (fmax) around 700 GHz (0.7 THz).
 - Demonstration of manufacturability and integratability with CMOS
 - Demonstration of capabilities and benefits of 0.7 THz SiGe HBT technology by benchmark circuits and system applications in the 0.1 to 1 THz range
- 6 European countries, 13 partners
- 42 months duration: from 01.10.2012 to 31.03.2016
- EC grant: 8.600.000€ for a budget of ~12M€
- Coordinator:
 - Rudolf Lachner INFINEON,
 - Deputy : Klaus Aufinger INFINEON
 - Technical Director: Michael Schroter, University Dresden, San Diego



Overview

- This workshop will cover SiGe HBT technologies as well as SiGe enabled mm-wave and THz applications.
- SiGe technologies have passed the 600 GHz barrier in terms of maximum oscillation frequency and the 700 GHz barrier is foreseen to fall in 2015.
- Intrinsic advantages of SiGe HBTs:
 - co-integration with CMOS
 - => design of compact, reliable and cost efficient systems for mm-wave applications.
- 4 sessions (with 2 (3) speakers each)
 - Session 1: World-leading SiGe technologies from Europe (9h10-10h40)
 - Coffee Break: 10h40-11h20
 - Session 2: Compact modelling and design challenges for mm-wave and THz devices and circuits (11h20-12h50)
 - Buffet Lunch Break: 12h50-14h20
 - Session 3: Radar related innovative design concepts (14h20-16h00)
 - Coffee Break: 16h00-16h30
 - Session 4: Application challenges and potential solutions for qualified products (16h30-18h00)
 - 18:00 18:20 Open discussion and concluding remarks
- Download the slides @:

http://www.iee.et.tu-dresden.de/iee/eb/res/dot7/dot7.html

Or send a mail: thomas.zimmer@ieee.org



Session 1: World-leading SiGe technologies from Europe

- 9:10 09:40 "Advances in SiGe BiCMOS Technology for mm-Wave Applications in the DOTSEVEN Project"
 - Klaus Aufinger, Infineon, Germany
- 9:40 10:10 "55nm SiGe BiCMOS for Optical, Wireless and High-Performance Analog Applications"
 - Pascal Chevalier, STMicroelectronics, France
- 10:10 10:40 "Optimization of vertical doping profiles for high-speed SiGe HBTs"
 - Holger Rücker, IHP, Germany

Session 2: Compact modelling & design www.2015 challenges for mm-wave/THz devices & circuits

- •11:20 12:05 "Impact of physical effects and compact modeling on mm-wave circuit performance"
 - Andreas Pawlak, Dresden University of Technology, Germany
- •12:05 12:50 "Challenges in Modeling, Design, and Characterization of Terahertz Circuits in Silicon"
 - •Ullrich Pfeiffer, University of Wuppertal, Germany



Session 3: Radar related innovative design concepts

- •14:20 15:05 "From Adaptive Modulation Schemes towards Software Defined Radar (SDR)"
 - Andreas Stelzer, Johannes Kepler University Linz, Austria
- •15:05 16:00 "Concepts for Highly Integrated Automotive Radar Circuits"
 - Herbert Jäger, Infineon DICE GmbH & Co KG, Austria
 - •Matthias Porranzl, Johannes Kepler University Linz



Session 4: Application challenges and potential solutions for qualified products

- •16:30 17:15 "Beyond 10 Gbit/s mm-wave wireless communication using SiGe BiCMOS transceivers"
 - •Erik Öjefors, SiversIMA, Sweden
- •17:15 18:00 "Application challenges and potential solutions for robust radar sensors"
 - •Dirk Steinbuch, Bosch, Germany



Annoucement: Seminar

- •Title: SiGe-THz devices: Physics and reliability
- Place: University of Bordeaux, France
 - 351 cours de la Liberation, IMS, Bat A31, Amphitheatre J.-P. Dom
- •Date: December 17, 2015
- Preliminary Programme
 - •Session 1: Physics based device simulation (9h15-10h45),
 - Christoph Jungemann, RWTH Aachen University
 - Session 2: Safe operating limits of SiGe-THz devices (11h00-12h30),
 - Anjan Chakravorty, IIT Madras, India
 - •Session 3: Reliability of SiGe-THz devices (14h00-15h30),
 - Grazia Sasso, University of Naples, Italy
 - •Session 4: Reliability aware circuit design (15h45-17h15),
 - Cristell Maneux, University of Bordeaux, France
- Contact: thomas.zimmer@ims-bordeaux.fr



Acknowledgement

The DOT7 project has received funding from the European Union's Seventh Programme for research, technological development and demonstration under grant agreement No 316755

Thanks to the EuMIC committee for hosting this WS.